


<b>Search Notes</b> 	<b>Application/Control No.</b> 10779858	<b>Applicant(s)/Patent Under Reexamination</b> MEYER, FRANK
	<b>Examiner</b> Ponikiewski, Tomasz	<b>Art Unit</b> 2165

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
updated search	3/21/07	TP
consulted with Neveen Abel-Jalil	3/21/07	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner